

M5M44800AJ,L,TP,RT-6,-7,-8,-10

FAST PAGE MODE 4194304-BIT(524288-WORD BY 8-BIT)DYNAMIC RAM

DESCRIPTION

This is a family of 524288-word by 8-bit dynamic RAMs, fabricated with the high performance CMOS process, and is ideal for large-capacity memory systems where high speed, low power dissipation, and low costs are essential. The use of quadruple-layer polysilicon process combined with silicide technology and a single-transistor dynamic storage stacked capacitor cell provide high circuit density at reduced costs. Multiplexed address inputs permit both a reduction in pins and an increase in system densities.

FEATURES

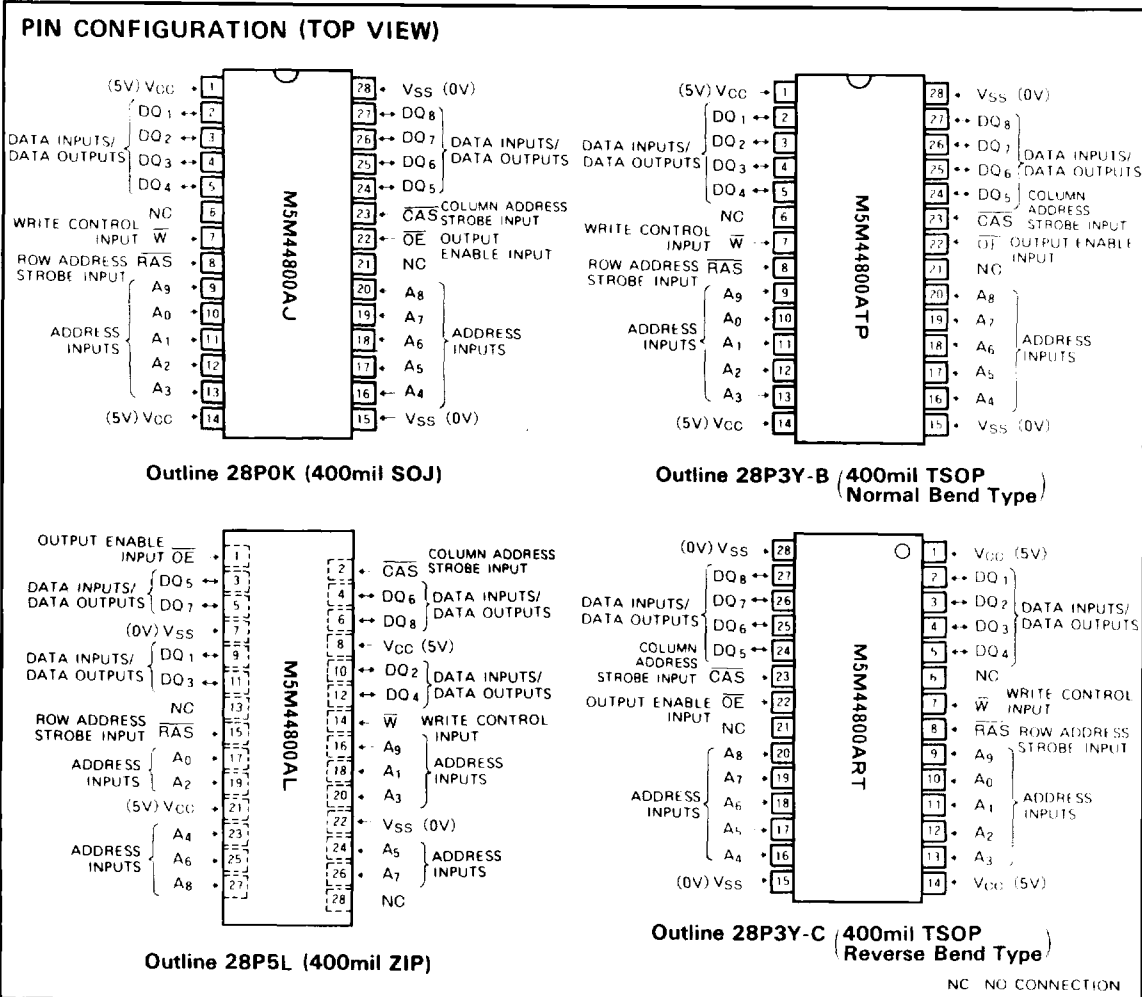
Type number	RAS access time (max. ns)	CAS access time (max. ns)	Address access time (max. ns)	OE access time (max. ns)	Cycle time (min. ns)	Power dissipation (typ. mW)
M5M44800AXX-6	60	15	30	15	120	500
M5M44800AXX-7	70	20	35	20	140	440
M5M44800AXX-8	80	20	40	20	160	375
M5M44800AXX-10	100	25	50	25	190	320

XX J, L, TP, RT

- 28 pin SOJ, 28 pin ZIP, 28 pin TSOP(II)
- Single 5V ± 10% supply
- Low stand-by power dissipation
5.5mW (max) CMOS Input level
- Low operating power dissipation
M5M44800AXX-6 660mW (max)
M5M44800AXX-7 578mW (max)
M5M44800AXX-8 495mW (max)
M5M44800AXX-10 412.5mW (max)
- Fast-page mode (512-bit random access), Read-modify-write, \overline{RAS} -only refresh, \overline{CAS} before \overline{RAS} refresh, Hidden refresh capabilities
- Early write mode and \overline{OE} to control output buffer impedance
- All inputs, output TTL compatible and low capacitance
- 1024 refresh cycles every 16.4ms ($A_0 \sim A_9$)

APPLICATION

Main memory unit for computers, Microcomputer memory, Refresh memory for CRT



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FUNCTION

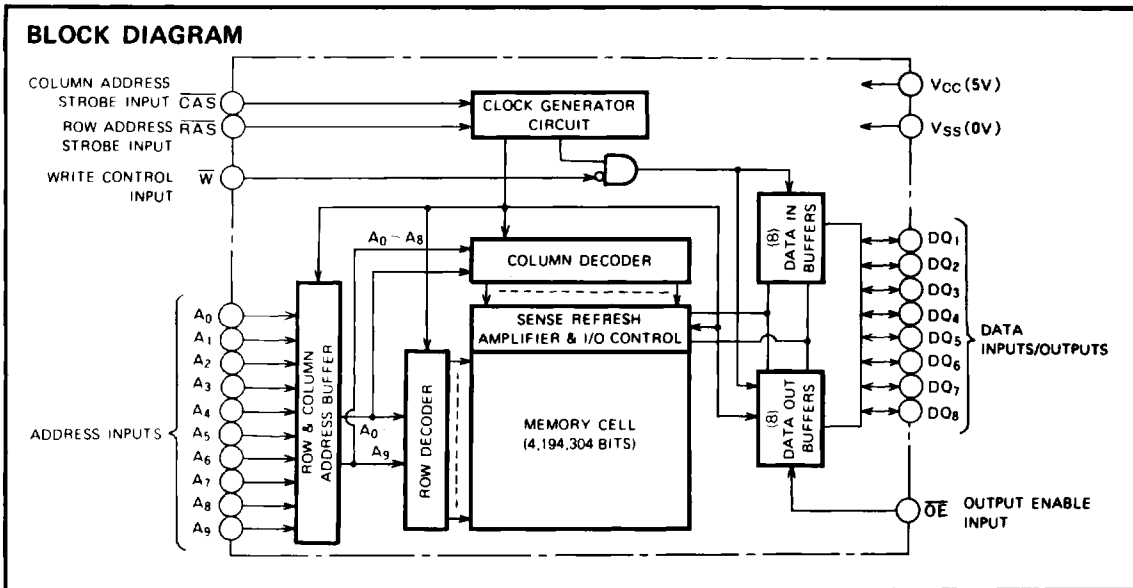
The M5M44800AJ, L, TP, RT provide, in addition to normal read, write, and read-modify-write operations,

a number of other functions, e.g., fast page mode, $\overline{\text{RAS}}$ -only refresh, and delayed-write. The input conditions for each are shown in Table 1.

Table 1 Input conditions for each mode

Operation	Inputs						Input/Output		Refresh	Remark
	RAS	$\overline{\text{CAS}}$	W	$\overline{\text{OE}}$	Row address	Column address	Input	Output		
Read	ACT	ACT	NAC	ACT	APD	APD	OPN	VLD	YES	Fast page mode identical
Write (Early write)	ACT	ACT	ACT	DNC	APD	APD	VLD	OPN	YES	
Write (Delayed write)	ACT	ACT	ACT	DNC	APD	APD	VLD	IVD	YES	
Read-modify-write	ACT	ACT	ACT	ACT	APD	APD	VLD	VLD	YES	
$\overline{\text{RAS}}$ only refresh	ACT	NAC	DNC	DNC	APD	DNC	DNC	OPN	YES	
Hidden refresh	ACT	ACT	DNC	ACT	DNC	DNC	OPN	VLD	YES	
$\overline{\text{CAS}}$ before $\overline{\text{RAS}}$ refresh	ACT	ACT	DNC	DNC	DNC	DNC	DNC	OPN	YES	
Stand-by	NAC	DNC	DNC	DNC	DNC	DNC	DNC	OPN	NO	

Note ACT: active, NAC: nonactive, DNC: don't care, VLD: valid, IVD: Invalid, APD: applied, OPN: open



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ABSOLUTE MAXIMUM RATINGS

Symbol	Parameter	Conditions	Ratings	Unit
V _{CC}	Supply voltage	With respect to V _{SS}	-1 ~ 7	V
V _I	Input voltage		-1 ~ 7	V
V _O	Output voltage		-1 ~ 7	V
I _O	Output current		50	mA
P _d	Power dissipation	T _a = 25°C	1000	mW
T _{opr}	Operating temperature		0 ~ 70	°C
T _{stg}	Storage temperature		-65 ~ 150	°C

RECOMMENDED OPERATING CONDITIONS (T_a = 0 ~ 70°C, unless otherwise noted) (Note 1)

Symbol	Parameter	Limits			Unit
		Min	Nom	Max	
V _{CC}	Supply voltage	4.5	5	5.5	V
V _{SS}	Supply voltage	0	0	0	V
V _{IH}	High level input voltage, all inputs	2.4		6.5	V
V _{IL}	Low level input voltage	DQs	-1.0	0.8	V
		Others	-2.0	0.8	

Note 1: All voltage values are with respect to V_{SS}.

ELECTRICAL CHARACTERISTICS (T_a = 0 ~ 70°C, V_{CC} = 5V ± 10%, V_{SS} = 0V, unless otherwise noted) (Note 2)

Symbol	Parameter	Test conditions	Limits			Unit
			Min	Typ	Max	
V _{OH}	High-level output voltage	I _{OH} = -5mA	2.4		V _{CC}	V
V _{OL}	Low level output voltage	I _{OL} = 4.2mA	0		0.4	V
I _{OZ}	Off state output current	Q floating 0V ≤ V _{OUT} ≤ 5.5V	-10		10	μA
I _I	Input current	0V ≤ V _{IN} ≤ 6.5V Other inputs pins = 0V	-10		10	μA
I _{CC1(AV)}	Average supply current from V _{CC} operating (Note 3, 4, 5)	M5M44800A-6			120	mA
		M5M44800A-7	RAS, CAS cycling		105	
		M5M44800A-8	t _{RC} = t _{WC} = min. output open		90	
		M5M44800A-10			75	
I _{CC2}	Supply current from V _{CC} , stand-by (Note 6)	RAS = CAS = V _{IH} , output open			2	mA
		RAS = CAS = V _{CC} - 0.5			1	
I _{CC3(AV)}	Average supply current from V _{CC} refreshing (Note 3, 5)	M5M44800A-6			120	mA
		M5M44800A-7	RAS cycling, CAS = V _{IH}		105	
		M5M44800A-8	t _{RC} = min. output open		90	
		M5M44800A-10			75	
I _{CC4(AV)}	Average supply current from V _{CC} Fast-Page-Mode (Note 3, 4, 5)	M5M44800A-6			120	mA
		M5M44800A-7	RAS = V _{IL} , CAS cycling		105	
		M5M44800A-8	t _{PC} = min. output open		90	
		M5M44800A-10			75	
I _{CC6(AV)}	Average supply current from V _{CC} CAS before RAS refresh mode (Note 3)	M5M44800A-6			105	mA
		M5M44800A-7	CAS before RAS refresh cycling		95	
		M5M44800A-8	t _{RC} = min. output open		80	
		M5M44800A-10			65	

- Note 2: Current flowing into an IC is positive, out is negative.
 3: I_{CC1(AV)}, I_{CC3(AV)} and I_{CC4(AV)} are dependent on cycle rate. Maximum current is measured at the fastest cycle rate.
 4: I_{CC1(AV)} and I_{CC4(AV)} are dependent on output loading. Specified values are obtained with the output open.
 5: Column Address can be changed once or less while RAS = V_{IL} and CAS = V_{IH}.

CAPACITANCE (T_a = 0 ~ 70°C, V_{CC} = 5V ± 10%, V_{SS} = 0V, unless otherwise noted)

Symbol	Parameter	Test conditions	Limits			Unit
			Min	Typ	Max	
C _{I(A)}	Input capacitance, address inputs	V _I = V _{SS}			5	pF
					7	
C _{I(CLK)}	Input capacitance, clock inputs	f = 1MHz			7	pF
					8	
C _{I/O}	Input/Output capacitance, data ports	V _I = 25mVrms			7	pF
					8	



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SWITCHING CHARACTERISTICS ($T_a = 0 \sim 70^\circ\text{C}$, $V_{CC} = 5\text{V} \pm 10\%$, $V_{SS} = 0\text{V}$, unless otherwise noted, See notes 6, 13, 14)

Symbol	Parameter	Limits								Unit
		M5M44800A-6		M5M44800A-7		M5M44800A-8		M5M44800A-10		
		Min	Max	Min	Max	Min	Max	Min	Max	
t_{CAC}	Access time from \overline{CAS} (Note 7, 8)		15		20		20		25	ns
t_{RAC}	Access time from \overline{RAS} (Note 7, 9)		60		70		80		100	ns
t_{AA}	Column Address access time (Note 7, 10)		30		35		40		50	ns
t_{CPA}	Access time from \overline{CAS} precharge (Note 7, 11)		35		40		45		55	ns
t_{OEA}	Access time from \overline{OE} (Note 7)		15		20		20		25	ns
t_{CLZ}	Output low impedance time from \overline{CAS} low (Note 7)	5		5		5		5		ns
t_{OFF}	Output disable time after \overline{CAS} high (Note 12)	0	15	0	20	0	20	0	25	ns
t_{OEZ}	Output disable time after \overline{OE} high (Note 12)	0	15	0	20	0	20	0	25	ns

- Note 6 An initial pause of 500 μ s is required after power-up followed by a minimum of eight initialization cycles (any combination of cycles containing a \overline{RAS} clock such as \overline{RAS} -Only refresh). Note the \overline{RAS} may be cycled during the initial pause. And any 8 \overline{RAS} or $\overline{RAS}/\overline{CAS}$ cycles are required after prolonged periods (greater than 16.4 ms) of \overline{RAS} inactivity before proper device operation is achieved.
- 7 Measured with a load circuit equivalent to 2TTL loads and 100pF.
- 8 Assumes that $t_{RCD} \geq t_{RCD(max)}$ and $t_{ASC} \geq t_{ASC(max)}$.
- 9 Assumes that $t_{RCD} \leq t_{RCD(max)}$ and $t_{RAD} \leq t_{RAD(max)}$. If t_{RCD} or t_{RAD} is greater than the maximum recommended value shown in this table, t_{RAC} will increase by amount that t_{RCD} or t_{RAD} exceeds the value shown.
- 10 Assumes that $t_{RAD} \geq t_{RAD(max)}$ and $t_{ASC} \leq t_{ASC(max)}$.
- 11 Assumes that $t_{CP} \leq t_{CP(max)}$ and $t_{ASC} \geq t_{ASC(max)}$.
- 12 $t_{OFF(max)}$ and $t_{OEZ(max)}$ defines the time at which the output achieves the high impedance state ($I_{OUT} \leq \pm 10\mu\text{A}$) and is not reference to $V_{OH(min)}$ or $V_{OL(max)}$.

TIMING REQUIREMENTS (For Read, Write, Read-Modify-Write, Refresh, and Fast Page Cycles)

($T_a = 0 \sim 70^\circ\text{C}$, $V_{CC} = 5\text{V} \pm 10\%$, $V_{SS} = 0\text{V}$, unless otherwise noted, See notes 13, 14)

Symbol	Parameter	Limits								Unit
		M5M44800A-6		M5M44800A-7		M5M44800A-8		M5M44800A-10		
		Min	Max	Min	Max	Min	Max	Min	Max	
t_{REF}	Refresh cycle time		16.4		16.4		16.4		16.4	ms
t_{RP}	\overline{RAS} high pulse width	50		60		70		80		ns
t_{RCD}	Delay time, \overline{RAS} low to \overline{CAS} low (Note 15)	20	45	20	50	20	60	25	75	ns
t_{CRP}	Delay time, \overline{CAS} high to \overline{RAS} low	10		10		10		10		ns
t_{RPC}	Delay time, \overline{RAS} high to \overline{CAS} low	0		0		0		0		ns
t_{CPN}	\overline{CAS} high pulse width	10		10		10		10		ns
t_{RAD}	Column address delay time from \overline{RAS} low (Note 16)	15	30	15	35	15	40	20	50	ns
t_{ASR}	Row address setup time before \overline{RAS} low	0		0		0		0		ns
t_{ASC}	Column address setup time before \overline{CAS} low (Note 17)	0	10	0	10	0	15	0	20	ns
t_{RAH}	Row address hold time after \overline{RAS} low	10		10		10		15		ns
t_{CAH}	Column address hold time after \overline{CAS} low	15		15		15		20		ns
t_{DZC}	Delay time, data to \overline{CAS} low (Note 18)	0		0		0		0		ns
t_{DZO}	Delay time, data to \overline{OE} low (Note 18)	0		0		0		0		ns
t_{CDD}	Delay time, \overline{CAS} high to data (Note 19)	15		20		20		25		ns
t_{ODD}	Delay time, \overline{OE} high to data (Note 19)	15		20		20		25		ns
t_T	Transition time (Note 20)	1	50	1	50	1	50	1	50	ns

- Note 13. The timing requirements are assumed $t_T = 5\text{ns}$.
14. $V_{IH(min)}$ and $V_{IL(max)}$ are reference levels for measuring timing of input signals.
15. $t_{RCD(max)}$ is specified as a reference point only. If t_{RCD} is less than $t_{RCD(max)}$, access time is t_{RAC} . If t_{RCD} is greater than $t_{RCD(max)}$, access time is controlled exclusively by t_{CAC} or t_{AA} . $t_{RCD(min)}$ is specified as $t_{RCD(min)} = t_{RAH(min)} + 2t_T + t_{ASC(min)}$.
16. $t_{RAD(max)}$ is specified as a reference point only. If $t_{RAD} \geq t_{RAD(max)}$ and $t_{ASC} \leq t_{ASC(max)}$, access time is controlled exclusively by t_{AA} .
17. $t_{ASC(max)}$ is specified as a reference point only. If $t_{RCD} \geq t_{RCD(max)}$ and $t_{ASC} \geq t_{ASC(max)}$, access time is controlled exclusively by t_{CAC} .
18. Either t_{DZC} or t_{DZO} must be satisfied.
19. Either t_{CDD} or t_{ODD} must be satisfied.
20. t_T is measured between $V_{IH(min)}$ and $V_{IL(max)}$.

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Read and Refresh Cycles

Symbol	Parameter	Limits								Unit
		M5M44800A-6		M5M44800A-7		M5M44800A-8		M5M44800A-10		
		Min	Max	Min	Max	Min	Max	Min	Max	
t _{RC}	Read cycle time	120		140		160		190		ns
t _{RAS}	\overline{RAS} low pulse width	60	10000	70	10000	80	10000	100	10000	ns
t _{CAS}	\overline{CAS} low pulse width	15	10000	20	10000	20	10000	25	10000	ns
t _{CSH}	\overline{CAS} hold time after \overline{RAS} low	60		70		80		100		ns
t _{RSB}	\overline{RAS} hold time after \overline{CAS} low	15		20		20		25		ns
t _{RCS}	Read Setup time before \overline{CAS} low	0		0		0		0		ns
t _{RCH}	Read hold time after \overline{CAS} high (Note 21)	0		0		0		0		ns
t _{RRH}	Read hold time after \overline{RAS} high (Note 21)	10		10		10		10		ns
t _{RAL}	Column address to \overline{RAS} hold time	30		35		40		50		ns
t _{COH}	\overline{CAS} hold time after \overline{OE} low	15		20		20		25		ns
t _{ORH}	\overline{RAS} hold time after \overline{OE} low	15		20		20		25		ns

Note 21: Either t_{RCH} or t_{RRH} must be satisfied for a read cycle.

Write Cycle (Early Write and Delayed Write)

Symbol	Parameter	Limits								Unit
		M5M44800A-6		M5M44800A-7		M5M44800A-8		M5M44800A-10		
		Min	Max	Min	Max	Min	Max	Min	Max	
t _{WC}	Write cycle time	120		140		160		190		ns
t _{RAS}	\overline{RAS} low pulse width	60	10000	70	10000	80	10000	100	10000	ns
t _{CAS}	\overline{CAS} low pulse width	15	10000	20	10000	20	10000	25	10000	ns
t _{CSH}	\overline{CAS} hold time after \overline{RAS} low	60		70		80		100		ns
t _{RSB}	\overline{RAS} hold time after \overline{CAS} low	15		20		20		25		ns
t _{WCS}	Write setup time before \overline{CAS} low (Note 23)	0		0		0		0		ns
t _{WCH}	Write hold time after \overline{CAS} low	10		15		15		20		ns
t _{CWL}	\overline{CAS} hold time after \overline{W} low	15		20		20		25		ns
t _{RWL}	\overline{RAS} hold time after \overline{W} low	15		20		20		25		ns
t _{WP}	Write pulse width	10		15		15		20		ns
t _{DS}	Data setup time before \overline{CAS} low or \overline{W} low	0		0		0		0		ns
t _{DH}	Data hold time after \overline{CAS} low or \overline{W} low	10		15		15		20		ns
t _{DEH}	\overline{OE} hold time after \overline{W} low	15		20		20		25		ns

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Read-Write and Read-Modify-Write Cycles

Symbol	Parameter	Limits								Unit
		M5M44800A-6		M5M44800A-7		M5M44800A-8		M5M44800A-10		
		Min	Max	Min	Max	Min	Max	Min	Max	
t _{RWC}	Read write/read modify write cycle time (Note 22)	160		185		205		245		ns
t _{RAS}	RAS low pulse width	95	10000	115	10000	125	10000	155	10000	ns
t _{CAS}	CAS low pulse width	50	10000	65	10000	65	10000	80	10000	ns
t _{CSH}	CAS hold time after RAS low	95		115		125		155		ns
t _{RSH}	RAS hold time after CAS low	50		65		65		80		ns
t _{RCS}	Read setup time before CAS low	0		0		0		0		ns
t _{CWD}	Delay time, CAS low to W low (Note 23)	35		40		40		50		ns
t _{RWD}	Delay time, RAS low to W low (Note 23)	80		90		100		125		ns
t _{AWD}	Delay time, address to W low (Note 23)	50		55		60		75		ns
t _{CWL}	CAS hold time after W low	15		20		20		25		ns
t _{RWL}	RAS hold time after W low	15		20		20		25		ns
t _{WP}	Write pulse width	10		15		15		20		ns
t _{DS}	Data setup time before W low	0		0		0		0		ns
t _{DH}	Data hold time after W low	10		15		15		20		ns
t _{OEH}	OE hold time after W low	15		15		20		25		ns

Note 22 t_{RWC} is specified as t_{RWC(min)} = t_{RAC(max)} + t_{OD(min)} + t_{RWL(min)} + t_{RP(min)} + 4t_r.

23 t_{WCS}, t_{CWD}, t_{RWD} and t_{AWD} and t_{CPWD} are specified as reference points only. If t_{WCS} ≥ t_{WCS(min)} the cycle is an early write cycle and the DQ pins will remain high impedance throughout the entire cycle. If t_{CWD} ≥ t_{CWD(min)}, t_{RWD} ≥ t_{RWD(min)}, t_{AWD} ≥ t_{AWD(min)} and t_{CPWD} ≥ t_{CPWD(min)} (for fast page mode cycle only), the cycle is a read-modify-write cycle and the DQ will contain the data read from the selected address. If neither of the above condition (delayed write) of the DQ (at access time and until CAS or OE goes back to V_{IH}) is indeterminate.

Fast-Page Mode Cycle (Read, Early Write, Read-Write, Read-Modify-Write Cycle) (Note 24)

Symbol	Parameter	Limits								Unit
		M5M44800A-6		M5M44800A-7		M5M44800A-8		M5M44800A-10		
		Min	Max	Min	Max	Min	Max	Min	Max	
t _{PC}	Fast page mode read/write cycle time	40		45		50		60		ns
t _{PRWC}	Fast page mode read write/read modify write cycle time	75		95		100		115		ns
t _{RAS}	RAS low pulse width for read write cycle (Note 25)	100	100000	115	100000	135	100000	160	100000	ns
t _{CP}	CAS high pulse width (Note 26)	10	15	10	15	10	20	10	25	ns
t _{CPRH}	RAS hold time after CAS precharge	35		40		45		55		ns
t _{CPWD}	Delay time, CAS precharge to W low (Note 23)	35		40		45		55		ns

Note 24 All previously specified timing requirements and switching characteristics are applicable to their respective fast page mode cycle.

25 t_{RAS(min)} is specified as two cycles of CAS input are performed.

26 t_{CP(max)} is specified as a reference point only.

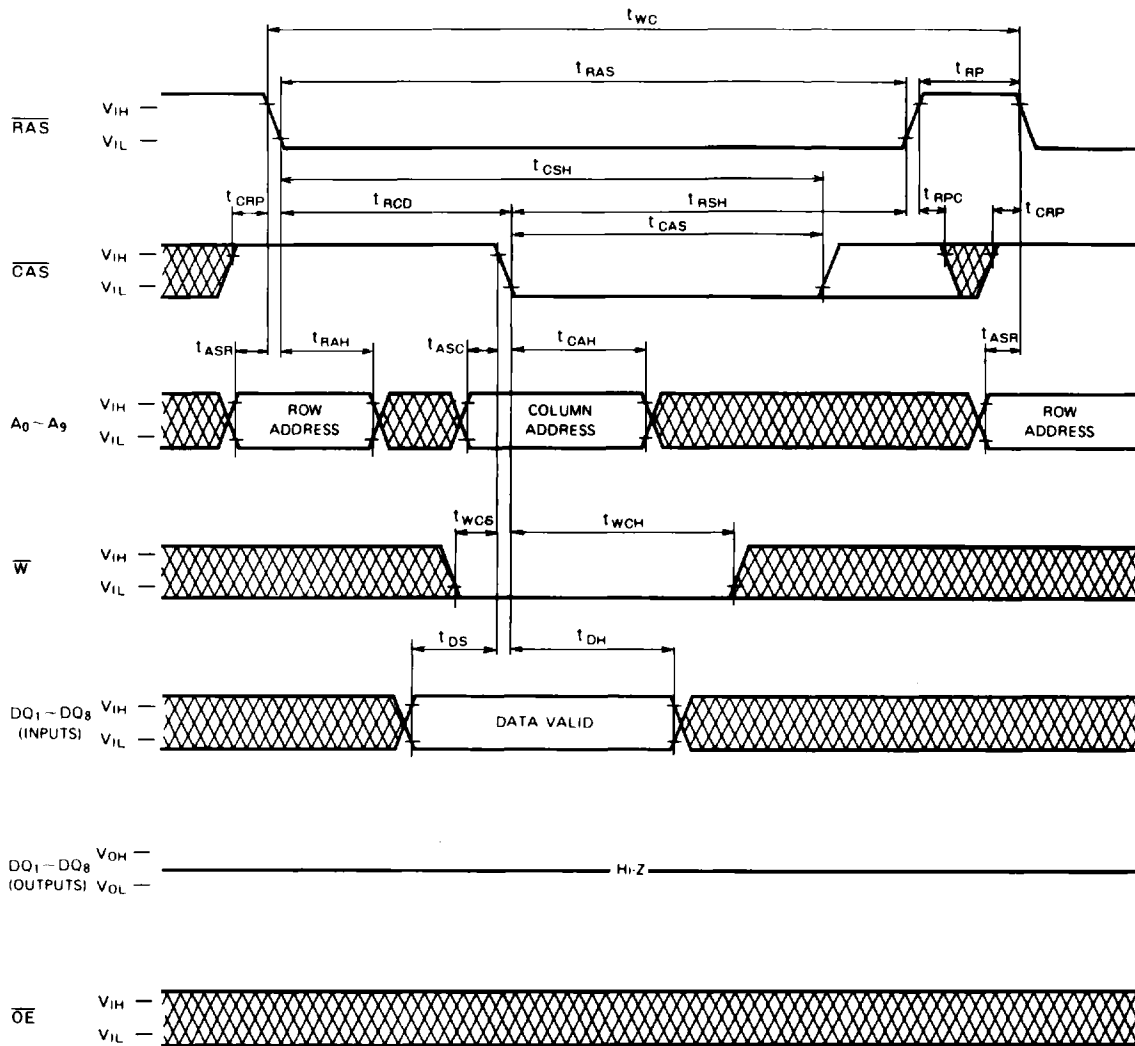
CAS before RAS Refresh Cycle (Note 27)

Symbol	Parameter	Limits								Unit
		M5M44800A-6		M5M44800A-7		M5M44800A-8		M5M44800A-10		
		Min	Max	Min	Max	Min	Max	Min	Max	
t _{CSR}	CAS setup time before RAS low	10		10		10		10		ns
t _{CHR}	CAS hold time after RAS low	10		15		15		20		ns
t _{RSR}	Read setup time before RAS low	10		10		10		10		ns
t _{RHR}	Read hold time after RAS low	10		15		15		20		ns

Note 27 Eight or more CAS before RAS cycles instead of eight RAS cycles are necessary for proper operation of CAS before RAS refresh mode.

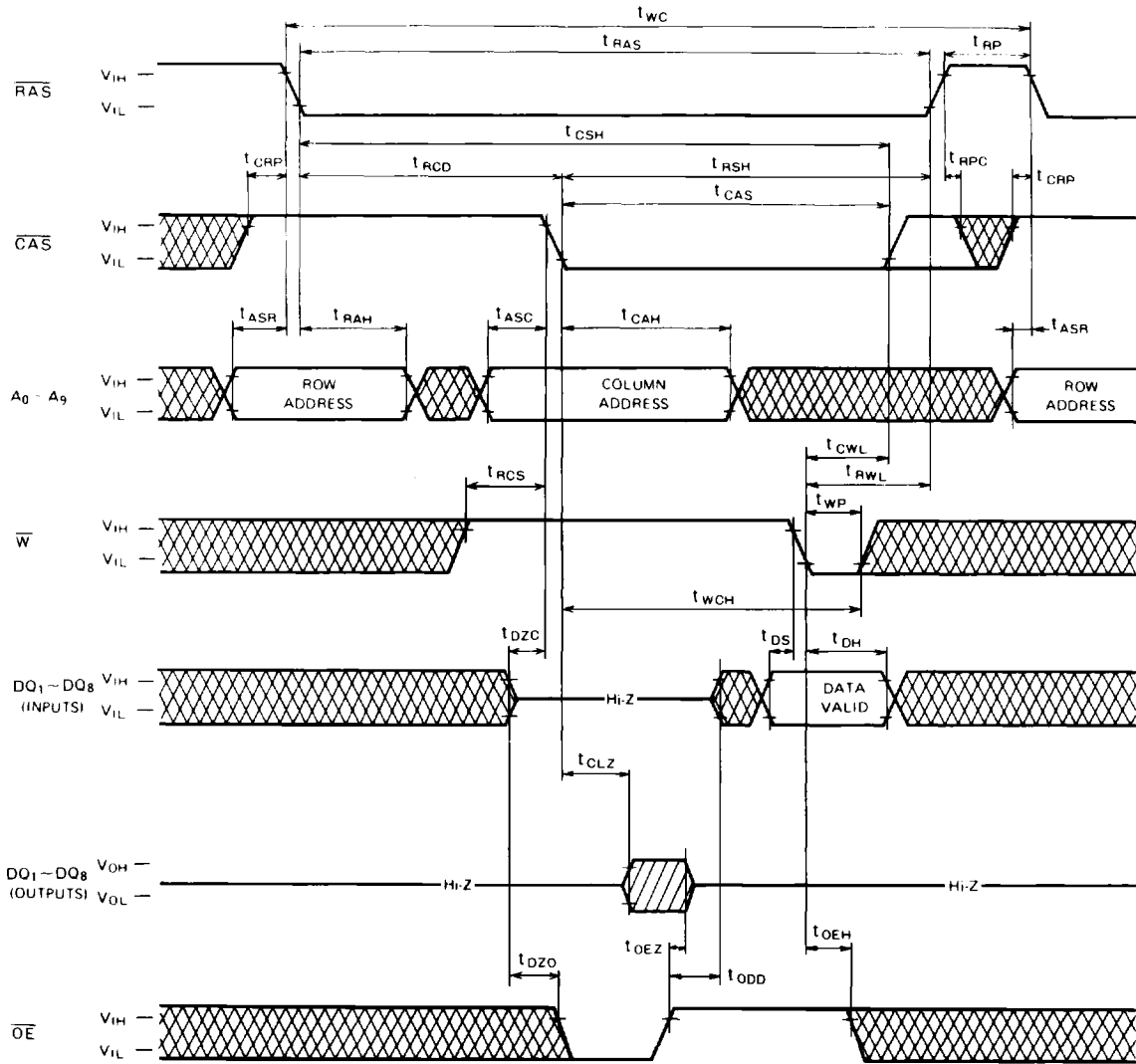
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Write Cycle (Early Write)



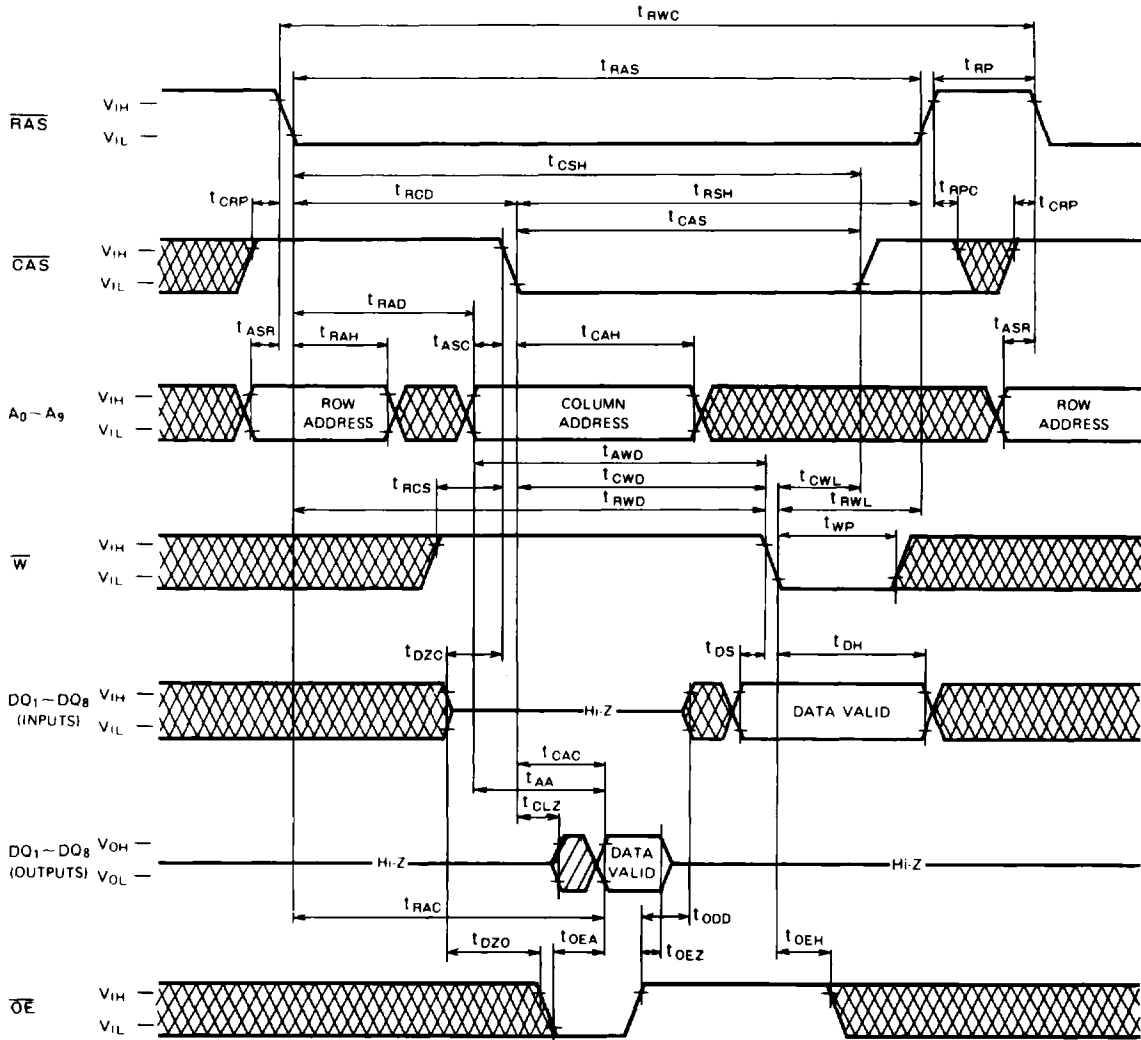
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Write Cycle (Delayed Write)



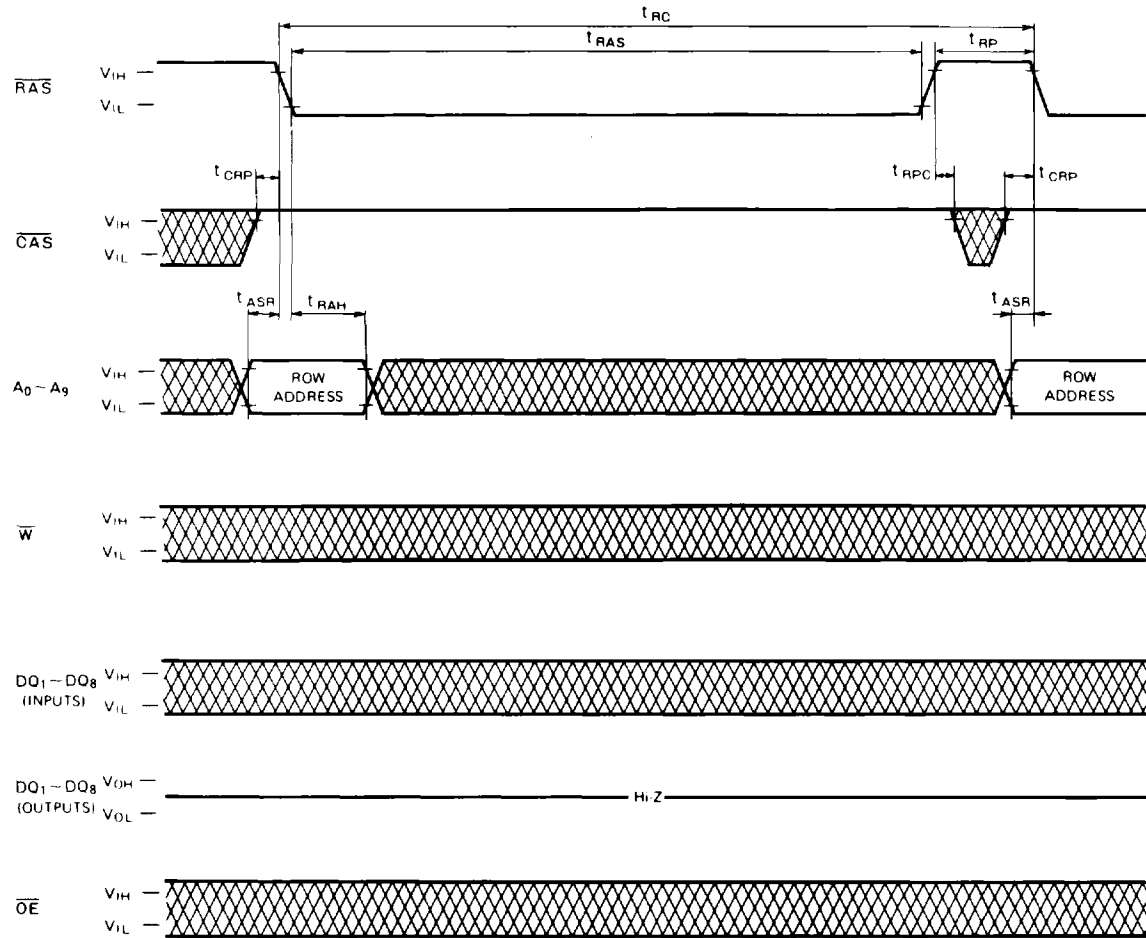
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Read-Write, Read-Modify-Write Cycle



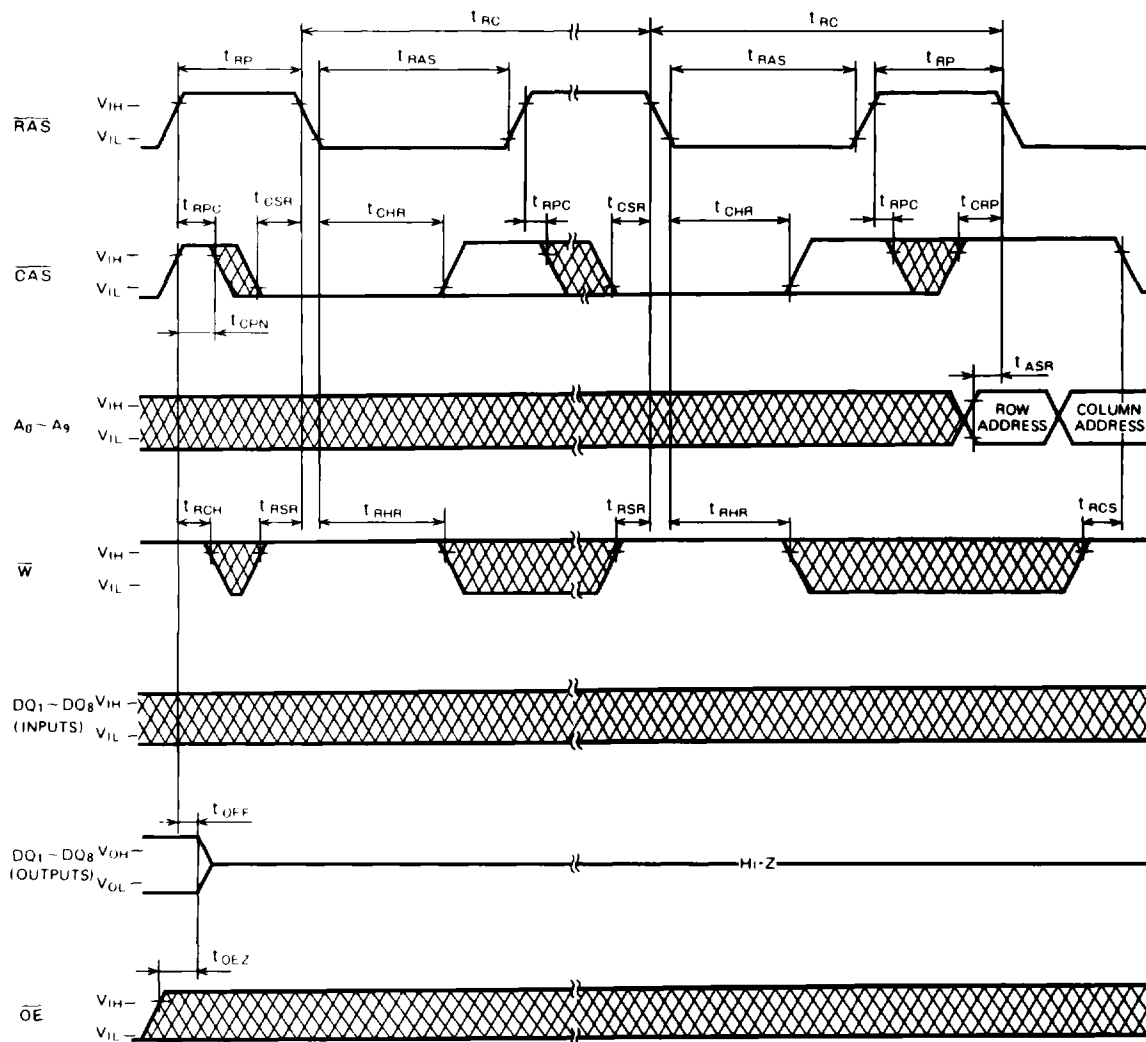
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RAS-only Refresh Cycle



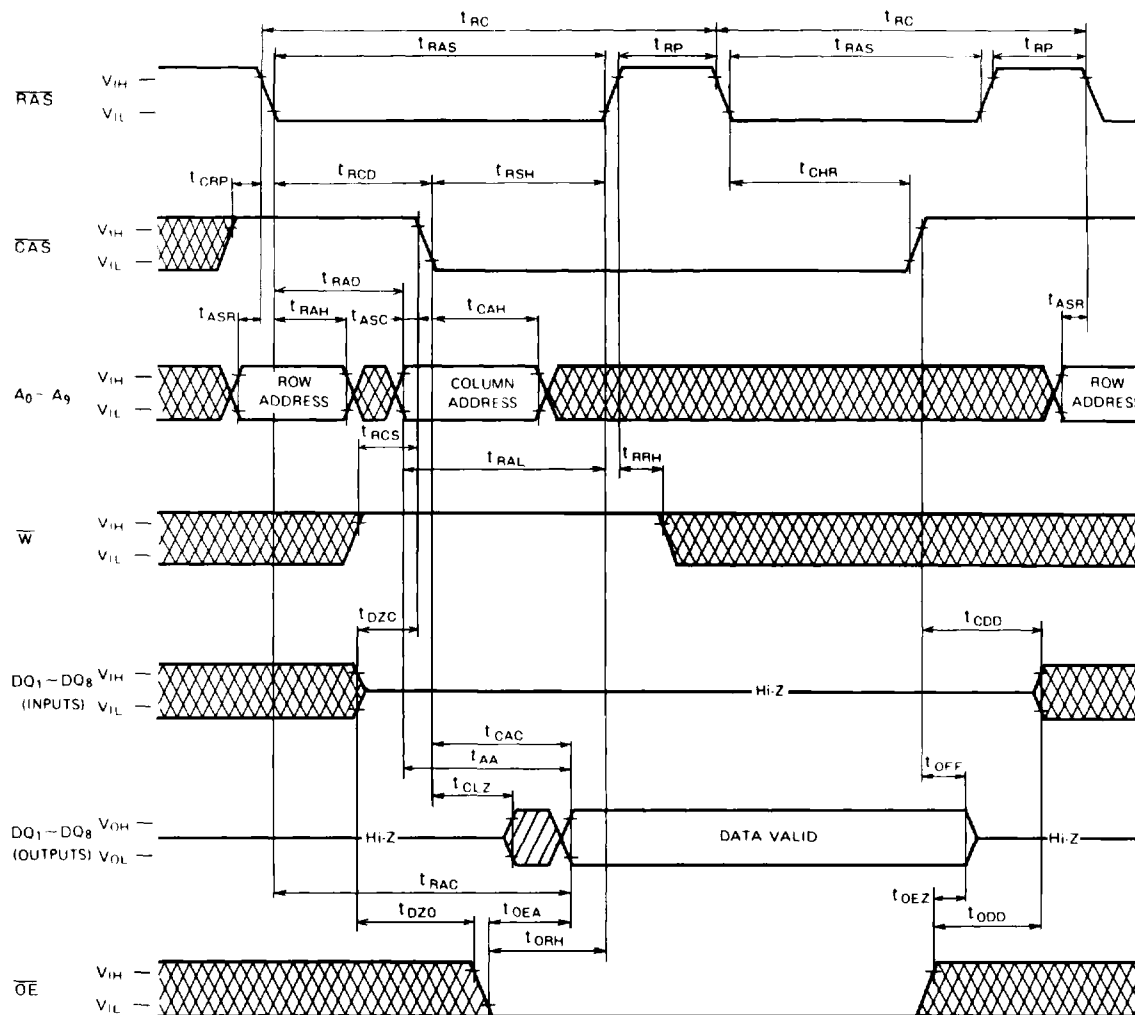
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$\overline{\text{CAS}}$ before $\overline{\text{RAS}}$ Refresh Cycle



FAST PAGE MODE 4194304-BIT(524288-WORD BY 8-BIT)DYNAMIC RAM

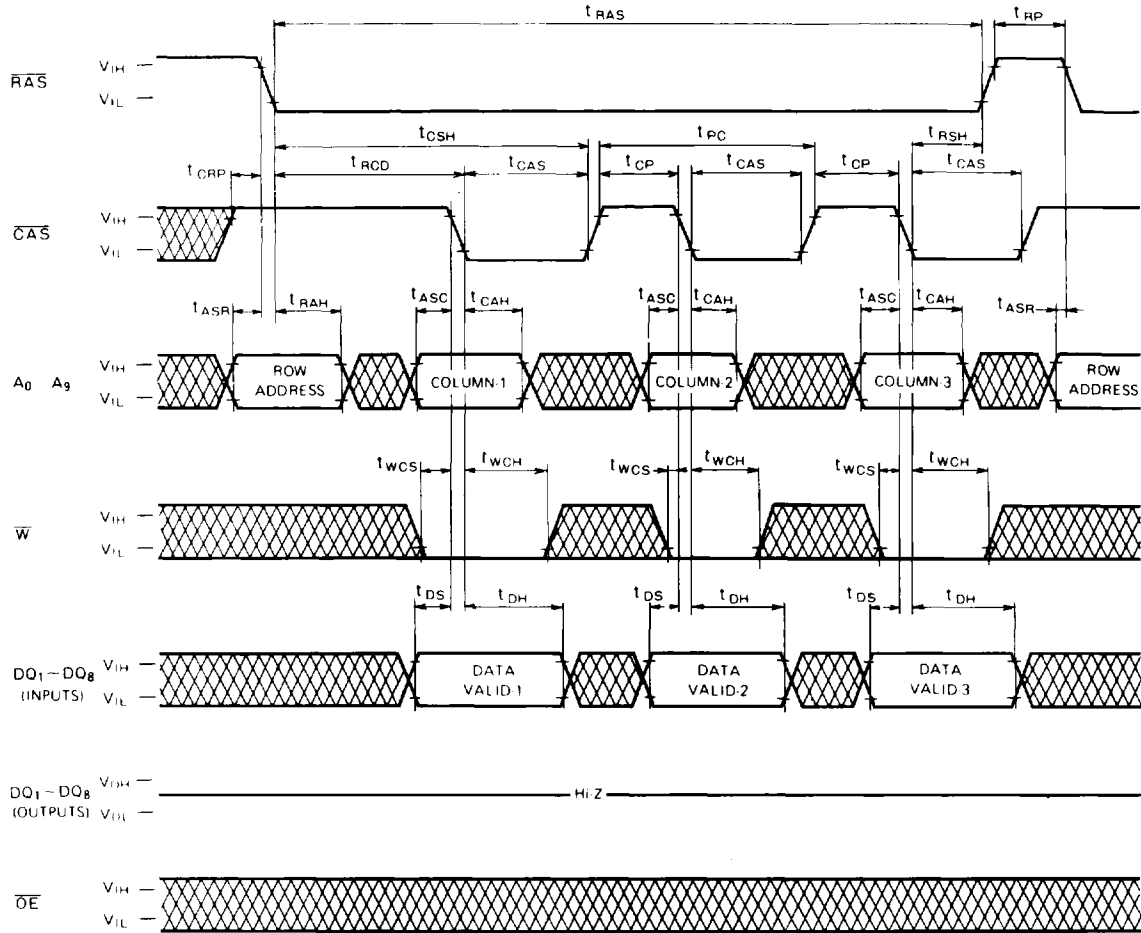
Hidden Refresh Cycle (Read) (Note 29)



Note 29: Early write, delayed write, read write or read modify write cycle is applicable instead of read cycle. Timing requirements and output state are the same as that of each cycle shown above.

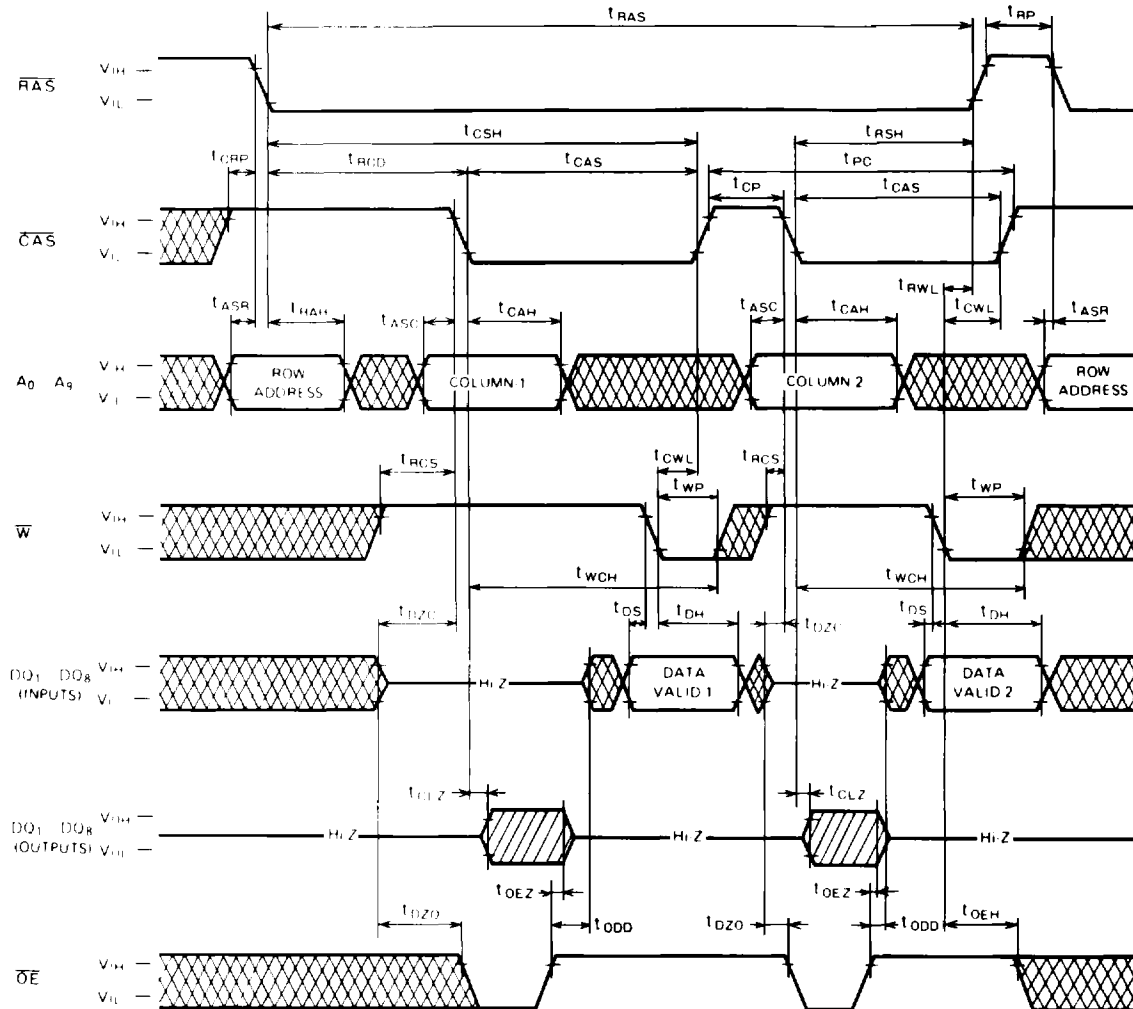
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Fast Page Mode Write Cycle (Early Write)



FAST PAGE MODE 4194304-BIT(524288-WORD BY 8-BIT)DYNAMIC RAM

Fast Page Mode Write Cycle (Delayed Write)



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FAST PAGE MODE 4194304-BIT(524288-WORD BY 8-BIT)DYNAMIC RAM

Fast Page Mode Read-Write, Read-Modify-Write Cycle

